



JCO4 Rec'd PCT/PTO - 2 AUG 2005

PATENT  
3511-1003

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Iiro HIETANEN et al.

Application No. 10/533,645

Filed May 3, 2005

SYNCRHONOUS OPTICAL MEASUREMENT  
AND INSPECTION METHOD AND MEANS

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

August 2, 2005

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed sheet.

A concise explanation of the relevance of these items is that these references were discovered during any searches they or their client had made, or that they were considered in the preparation of the application.

Respectfully submitted,

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RJP/lk

# **INFORMATION DISCLOSURE CITATION IN AN APPLICATION**

(Use several sheets if necessary)

Attorney Docket No.:  
**3511-1003**

Application No.:  
**10/533,645**

Applicant:  
**Iiro HIETANEN et al.**

Filing Date:  
**May 3, 2005**

Group Art Unit:

## **U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing date (if appropriate)
	4,937,449	06/26/1990	KREUZER et al.			
	5,991,046	11/23/1999	SHAKESPEARE et al.			

## **FOREIGN PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	EP 1 367 385	12/03/2003	EUROPE				
	DE 195 24 036	07/25/1996	GERMANY				
	GB 2 371 111	07/17/2002	GREAT BRITAIN				

## **OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**


EXAMINER:

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

\* Abstract provided for the Examiner's convenience